

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/596,966	SATO, HIDEO	
Examiner QUANG PHAM		Art Unit 2612	Page 1 of 1	

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2005/0081035 A1	04-2005	Togawa, Atsushi	713/171
*	B US-2004/0268131 A1	12-2004	Kudo et al.	713/182
*	C US-2002/0120668 A1	08-2002	Pintsov et al.	709/200
*	D US-2002/0154779 A1	10-2002	Asano et al.	380/277
*	E US-2004/0059685 A1	03-2004	Sakamura et al.	705/065
*	F US-2002/0166047 A1	11-2002	Kawamoto, Youji	713/169
*	G US-2003/0145203 A1	07-2003	Audebert et al.	713/169
*	H US-2003/0228886 A1	12-2003	Ishii et al.	455/558
*	I US-2005/0061875	03-2005	Zai et al.	235/383
*	J US-2005/0010769	01-2005	You et al.	713/168
*	K US-2004/0259499	12-2004	Oba et al.	455/041.2
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.